





U.S. UTILITY Patent Application

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O.I.P.E.	PATENT DATE		
SCANNED Am Q.A. A.G.			

APPLICATION NO. CLASS CONT/PRIOR SUBCLASS ART UNIT BORTH 09/631509 237.1 356 2877

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System and method for inspecting bumped wafers

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TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED		
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
☐ The term of this patent			NOTICE OF ALLOWANCE MAILED			
subsequent to (date) has been disclaimed.	(Assistant	Examiner)	(Date)			
The term of this patent shall not extend beyond the expiration date						
of U.S Patent. No.			ISSUE FEE			
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